

Modeling and Analysis of Extrusion-Spin Coating: An Efficient and Deterministic Process for Photoresist Coating Method in Microlithography



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PRESENTATION OUTLINE



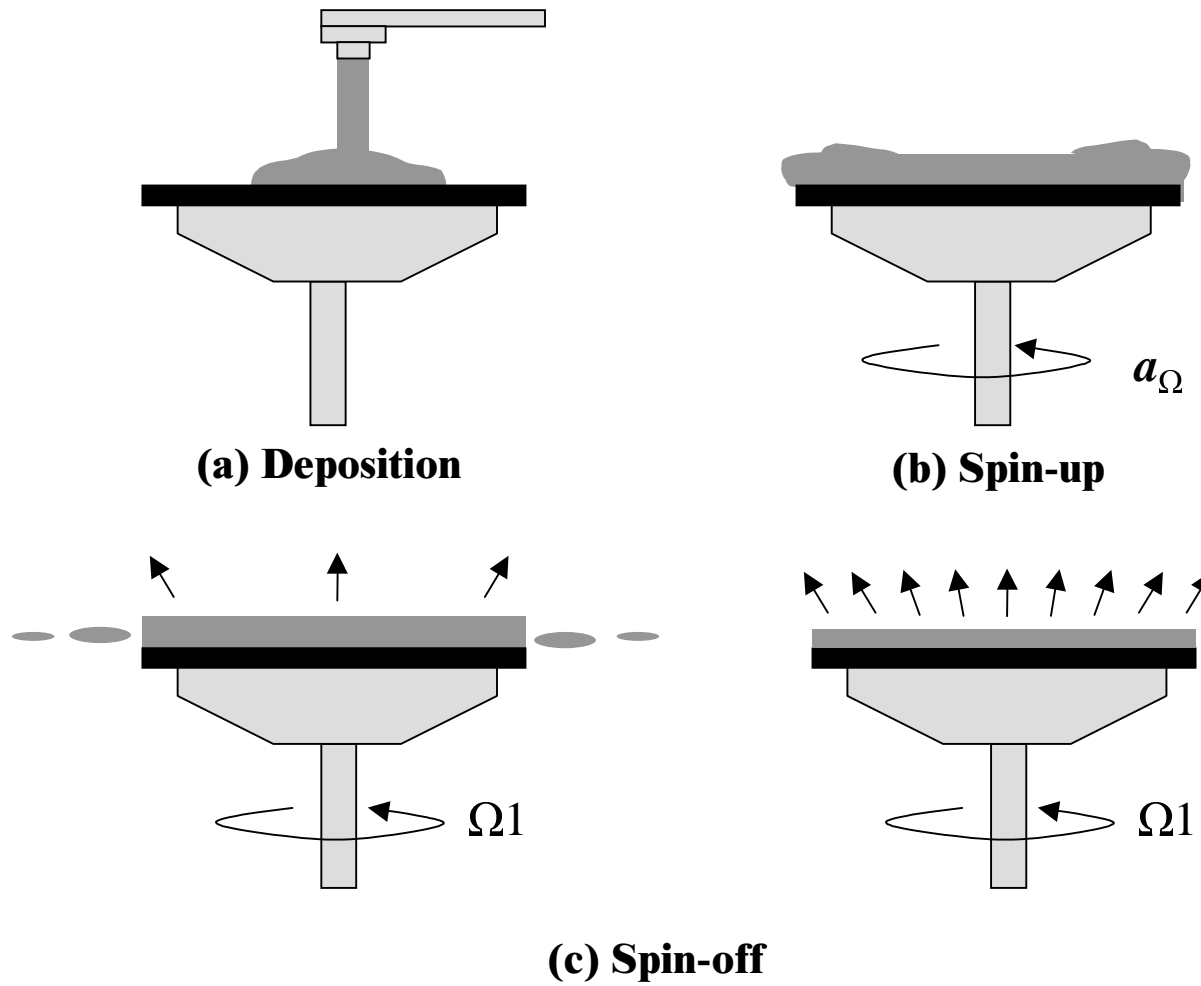
- **Introduction**
- **Extrusion-Spin Coating**
- **Modeling**
- **Experimental Apparatus**
- **Process Variables for Extrusion-Spin Coating**
- **Experimental Results and Analysis**
- **Conclusions and Future Work**

INTRODUCTION



- **Microolithography**
- **Spin Coating**
- **Problems with Spin Coating**
- **Motivation of Research**
- **Goals**
- **Comparison of Spin Coating and Extrusion-Spin Coating**

Spin Coating



Problems with Spin Coating

- **An initial coating layer is established using an inefficient coating method (~70% waste)**
- **Proper amount of photoresist to obtain specific coating thickness and uniformity is unpredictable**
 - **Photoresist is wasted if too much is applied**
 - **Incomplete coverage or defects occur if too little is applied ***

*: David J. Elliot. Microlithography: Process Technology for IC Fabrication. McGraw-Hill

Motivation of Research



- **Unpredictable coating thickness and uniformity**
- **Increase in cost of photoresist (\$500/gallon to \$2000/gallon)**
- **Environmental problem**

Goals



- **Improve photoresist coating efficiency**
(< 1 ml for 200mm wafer)
- **Maintain coating uniformity**
(Standard deviation σ of 6 Å within a wafer)
- **Develop a deterministic process to predict coating results**

Background

- **Key assumptions:**
 - **Wafers are initially entirely covered with photoresist**
 - **Properties of photoresist remain constant during coating process**

- **Spin coating models**
 - **Emslie et al. (without evaporation)**

$$h_f \sim \frac{h_0}{[1 + 4(\rho\omega^2/3\mu)h_0^2 t]^{1/2}}$$

- **Bornside et al. (with evaporation)**

$$h_f = (1 - x_0) \left[\frac{\mu_{PR}}{\rho\omega^2} \frac{p^* M}{R_g T} k x_0 \right]^{1/3}$$

Comparison of Spin Coating and Extrusion-Spin Coating

Conventional Spin Coating



Deposition: Deposit resist onto wafer



Spin-up: Accelerate wafer to obtain initial coating thickness



Spin-off: Spin at high speed to final thickness

Extrusion-Spin Coating



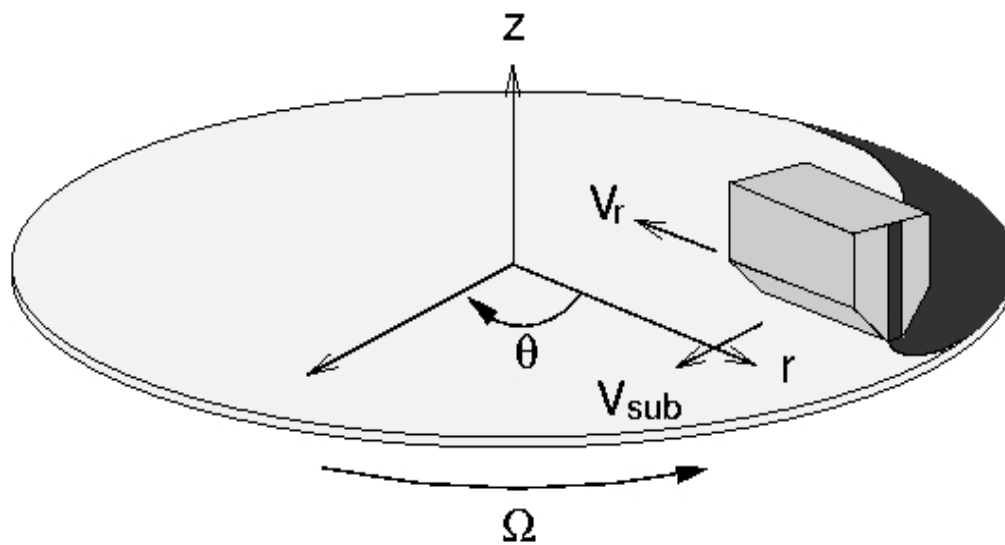
Deposition: Apply thin layer of resist by extrusion coating



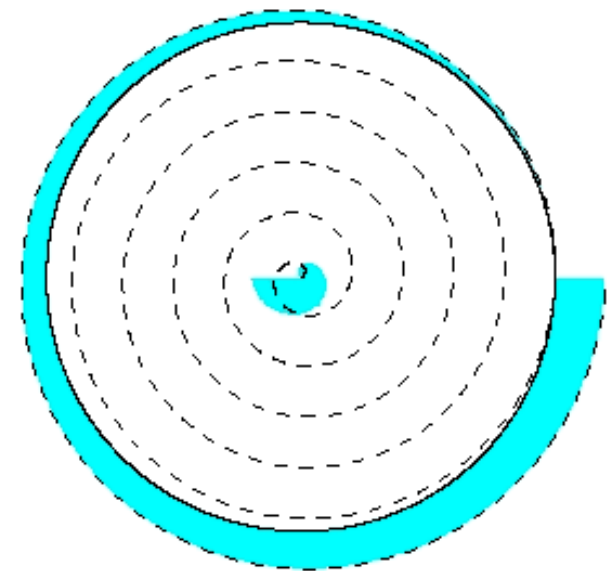
Spin-off: Spin at high speed to final thickness

EXTRUSION-SPIN COATING

Concept of Extrusion-Spin Coating



Spiral Coating



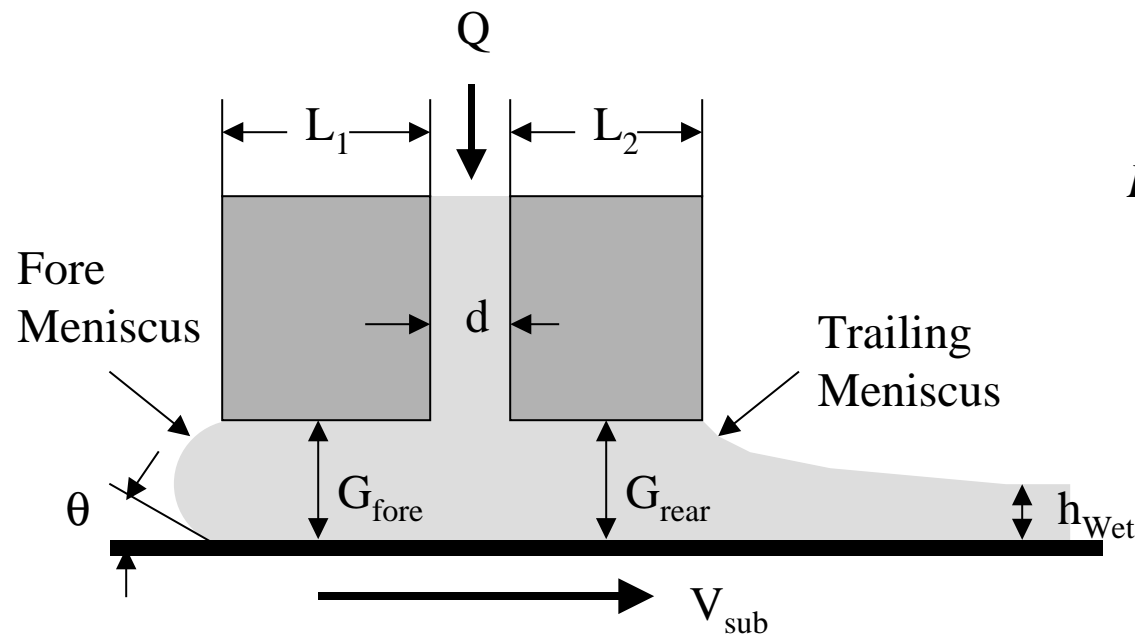
MODELING



- **Extrusion Coating**
 - **Schematic diagram of extrusion coating**
 - **Flow over a rotating disk during extrusion-spin coating**

- **Spin Coating**
 - **Coating chamber diagram**
 - **Flow regimes**

Schematic Diagram of Extrusion Coating



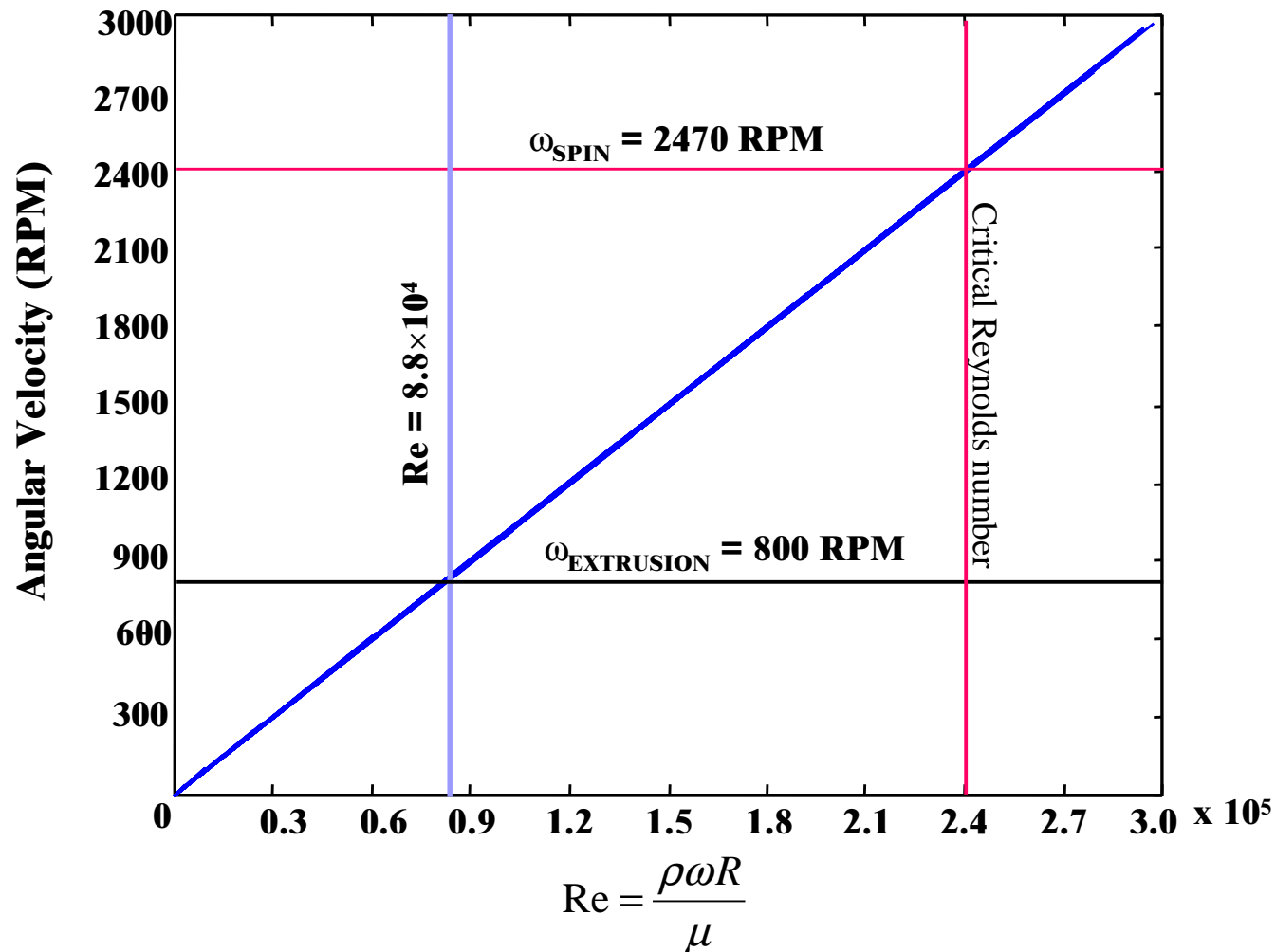
$$\text{Bead Coatability} \propto h / \mu V_{sub} G^*$$

$$h_{wet} = \frac{Q}{V_{sub} w}$$

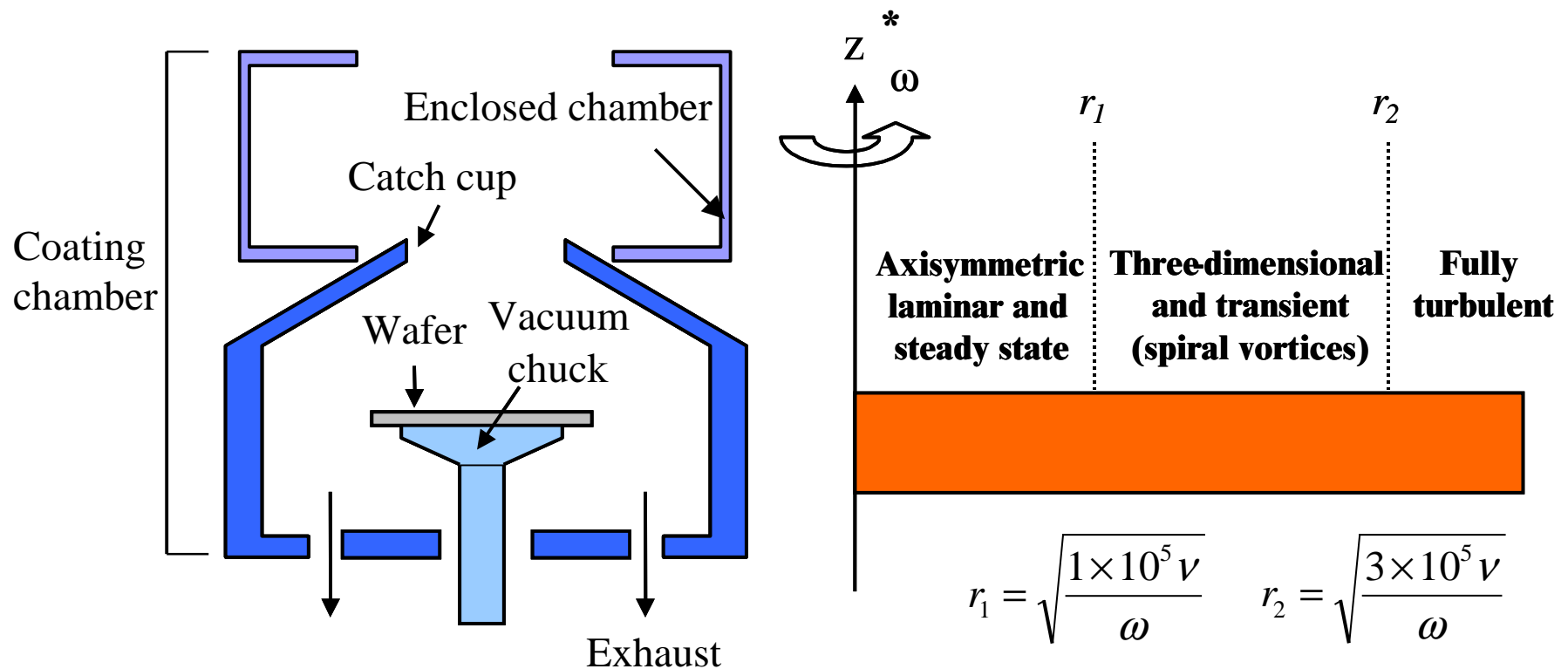
$$h_f = S_f h_{wet}$$

*: Edward J. Choinski. Patch coating: taking the spin out of thin. Information Display, 7(11), 1991

Flow over a Rotating Disk during Extrusion-Spin Coating for 200 mm Wafers



Coating Chamber and Flow over a Rotating Disk



*: David E. Bornside and Robert A. Brown. The effect of gas phase convection on mass transfer in spin coating. *Journal of Applied Physics*, 71(2), 15 January 1993.

PROCESS VARIABLES FOR EXTRUSION-SPIN COATING



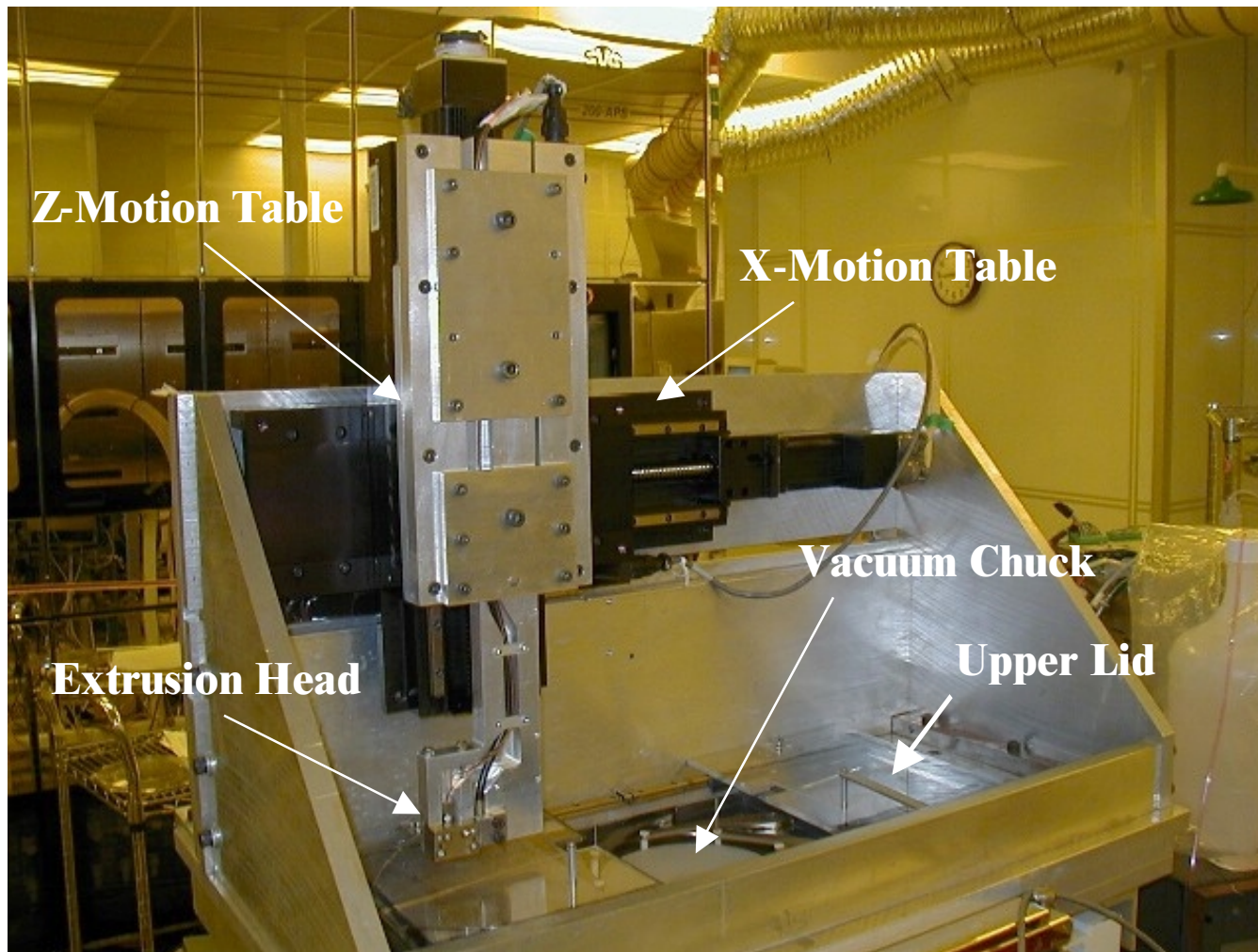
- **Solvent Concentration Degree: 0~100%**
- **Extrusion Coating Speed: 0~150 RPM**
- **Gap Distance: 40~100 μm**
- **Initial Coating Thickness: 10~40 μm**
- **High Spin Speed: 1500~3000 RPM**
- **High Spin Time: 20~50 sec**

EXPERIMENTAL RESULTS AND ANALYSIS



- **Properties of Photoresist**
- **Initial Experiments without Solvent Concentrated Environment**
- **Effect of Solvent Concentration on Coating Results**
- **Experimental Results with Solvent Concentrated Environment**

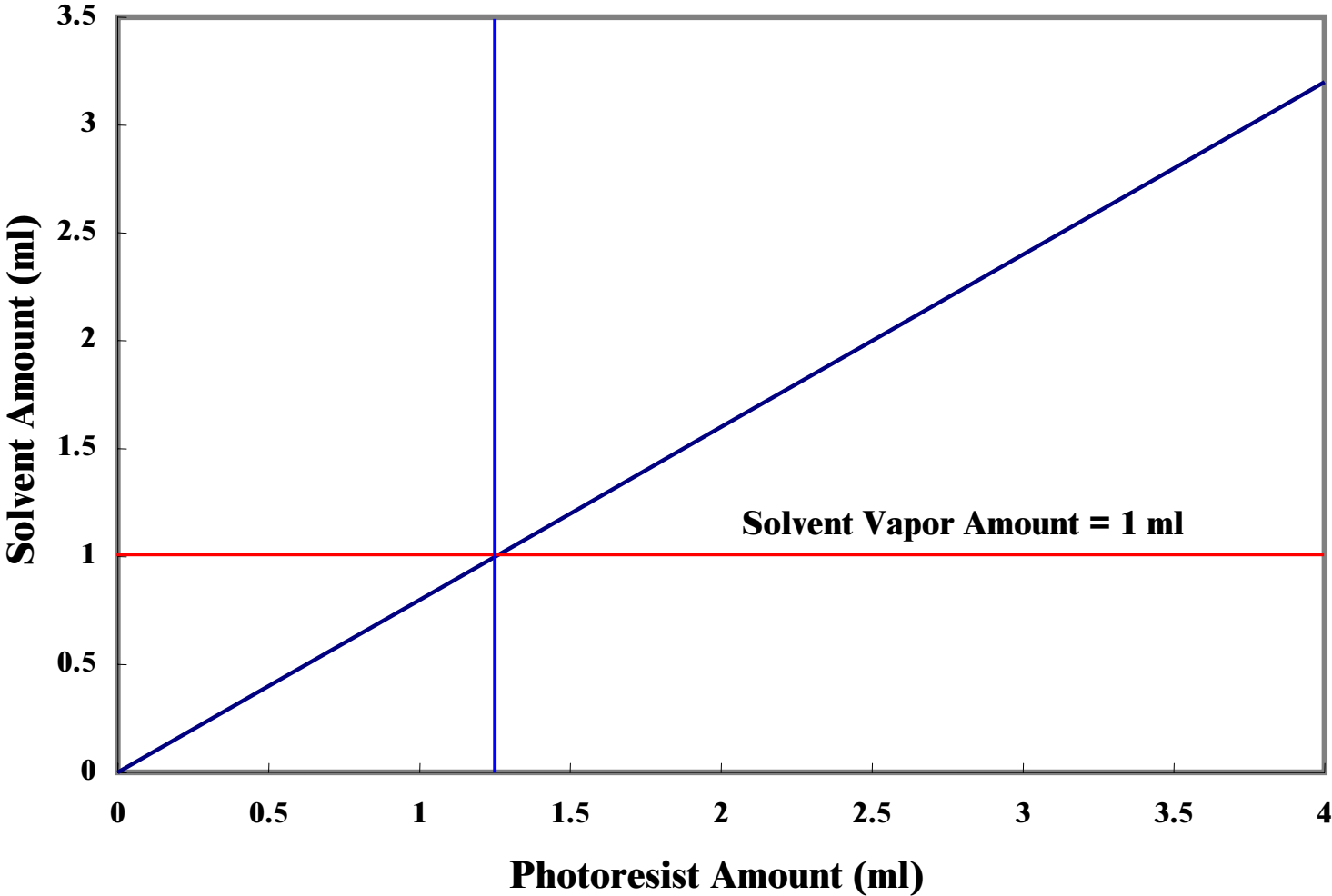
Prototype Extrusion-Spin Coater



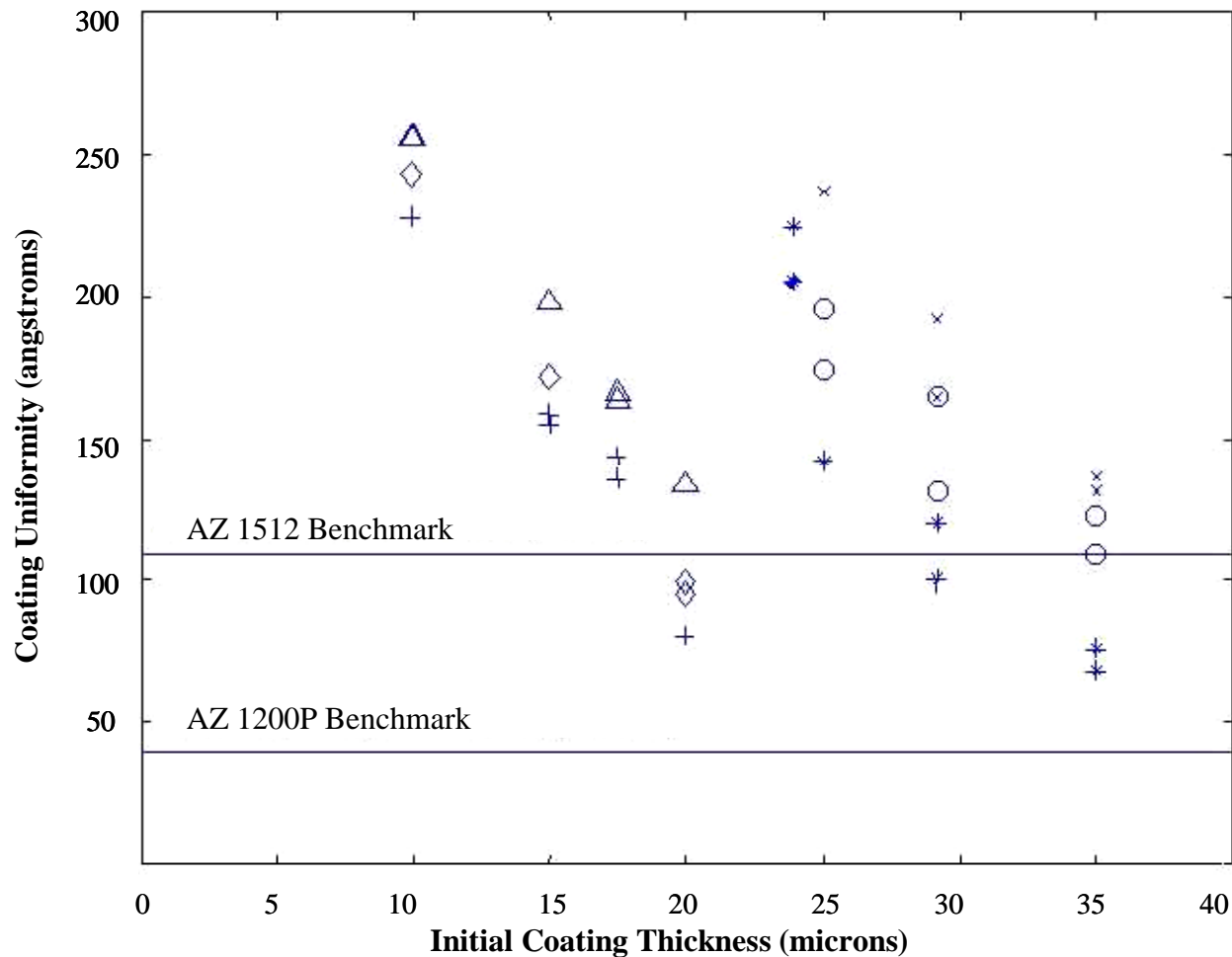
Properties of Photoresist

	AZ1512	AZ 1200P	Water
Density (kg/m³)	1040	1000	1000
Viscosity (mPA-sec)	19	11	1
Surface Tension (N/km)	32	30	74
Solid Contents (%)	26	20	NA
Price/Gallon (\$)	500	2000	

Solvent Amount vs. Photoresist Amount



Coating Uniformity without Any Solvent Concentrated Environment



AZ1512 (19cp)

***: Initial coating time (~21 sec)**

o: ~3 sec delay time

x: ~5 sec delay time

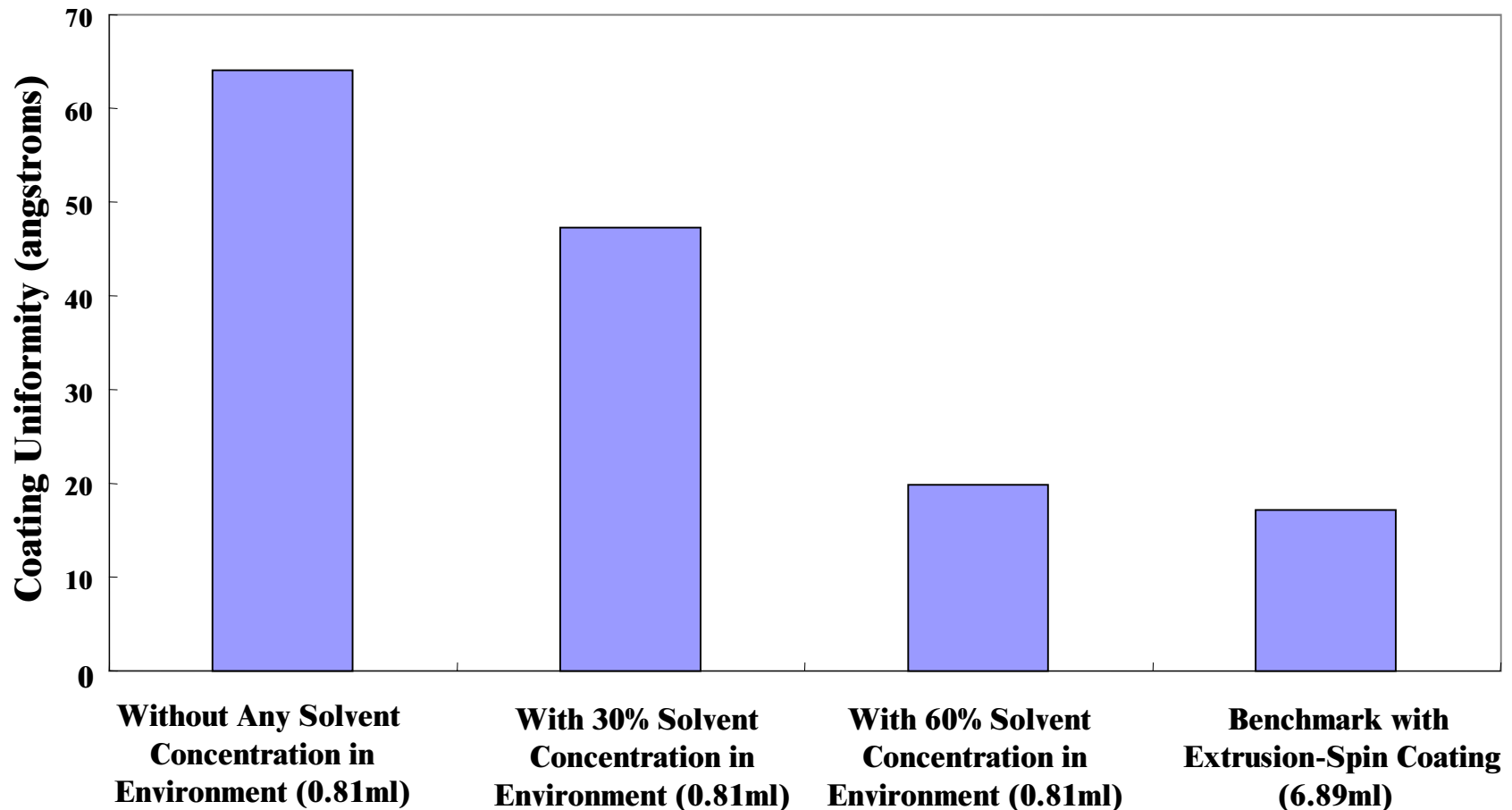
AZ1200P (11cp)

+: Initial coating time (~17 sec)

◇: ~3 sec delay time

△: ~5 sec delay time

Effect of Solvent Concentration on Coating Uniformity: Initial Test (1998)



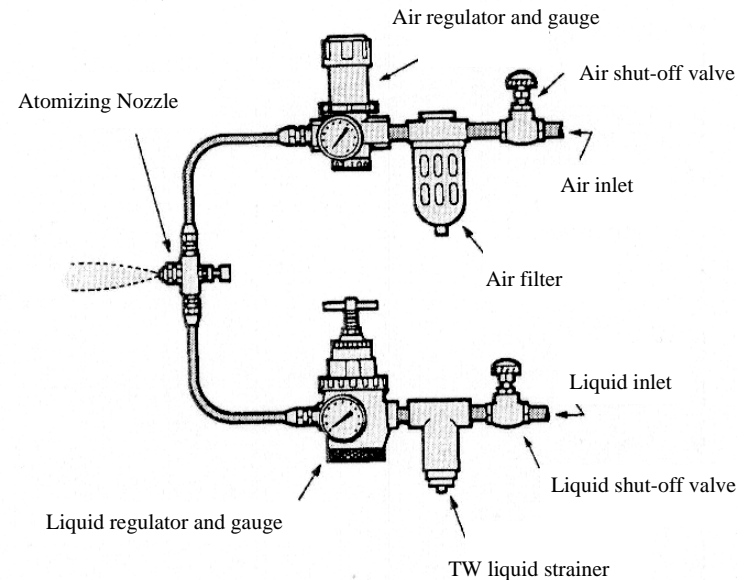
Solvent Concentrated Environment

- **Solvent: Propylene Glycol Mono-methyl Ether Acetate (PGMEA)**

- **Molecular weight: 132.2**
- **Density: 0.00543 g/cm³**
- **Viscosity: 62 μP ***
- **Vapor pressure at 20°C: 3.7 mm HG**
- **Diffusion coefficients:**
 - **$D_{PGMEA>Air} = 6.67 \times 10^{-6} \text{ m}^2/\text{sec}$**

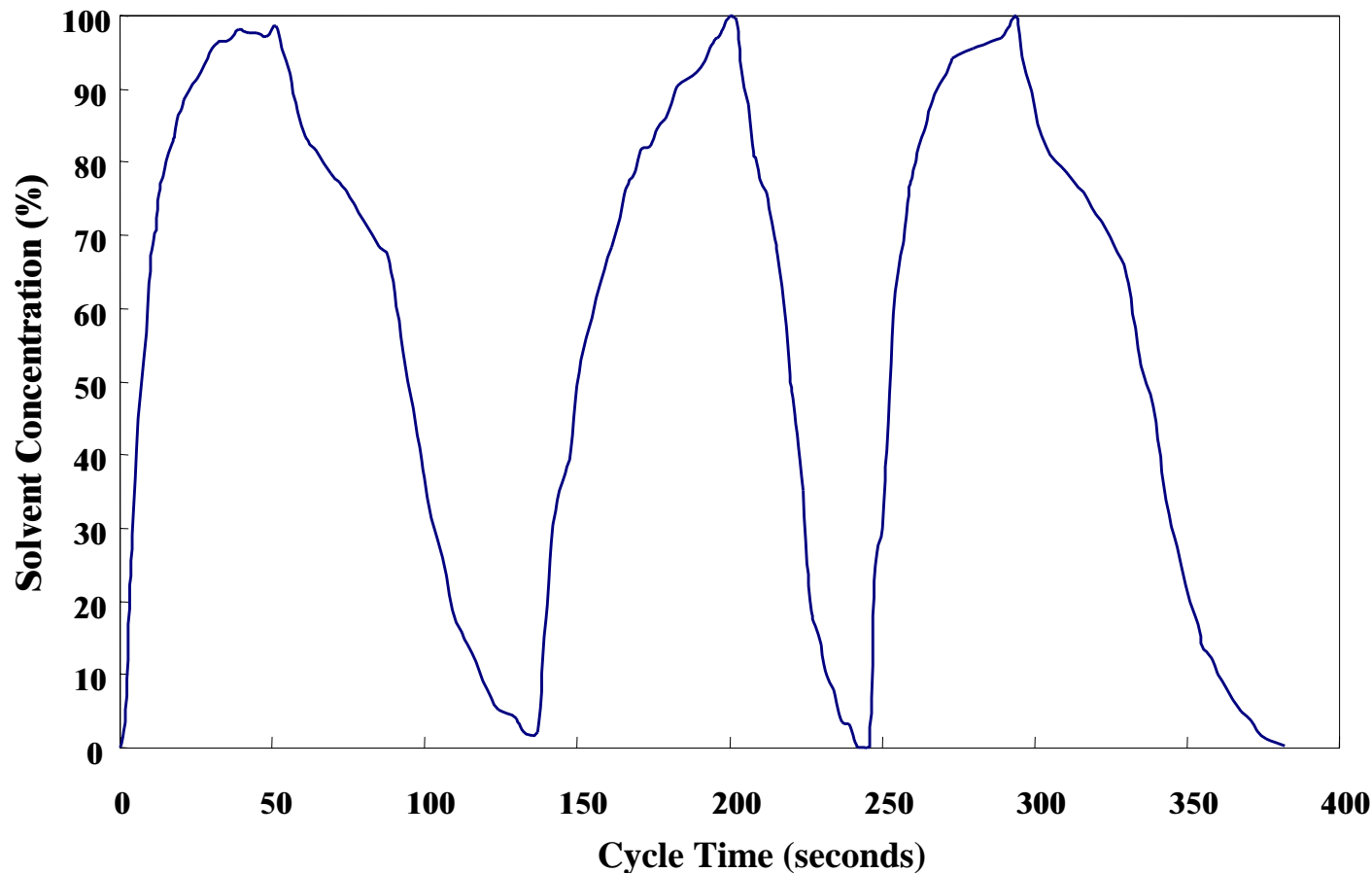
*: R. Reid, Properties of Gases and Liquids, McGraw Hill

- **Solvent Vaporizing Equipment: Atomizer**



- **Metrology tool: Berkeley Micro Instruments BMC200 Chemical Vapor Sensor**

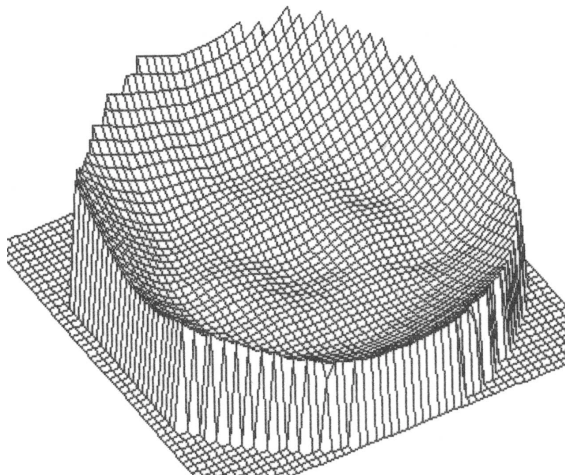
Solvent Concentration Measurements



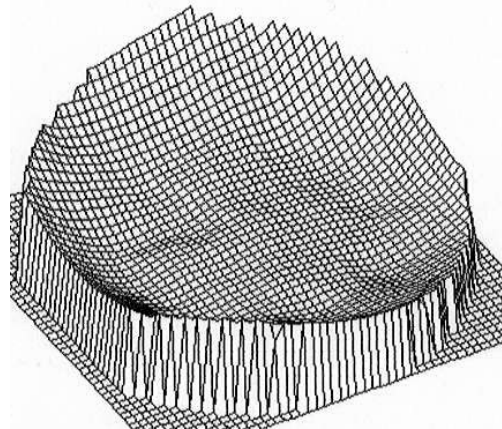
Exhaust valve was maintained closed throughout the entire coating cycle (extrusion + spin coating) in first and third experiments. Exhaust valve was closed during extrusion coating and turned open during the spin coating cycle in second experiments.

Coating Thickness Profile

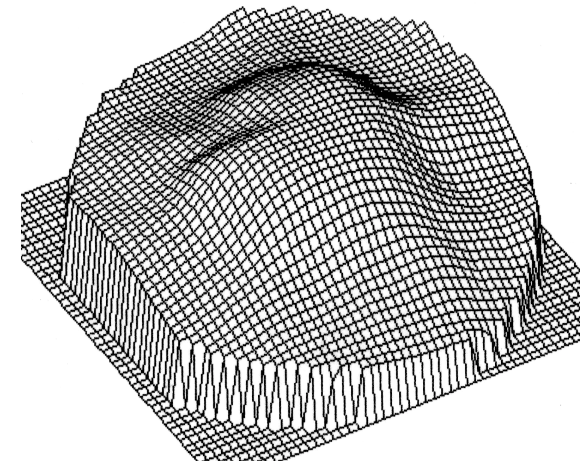
1 μm
100 mm



Spin coated at 3000 RPM
in 0% solvent
concentrated environment:
7718 μm with 78 \AA

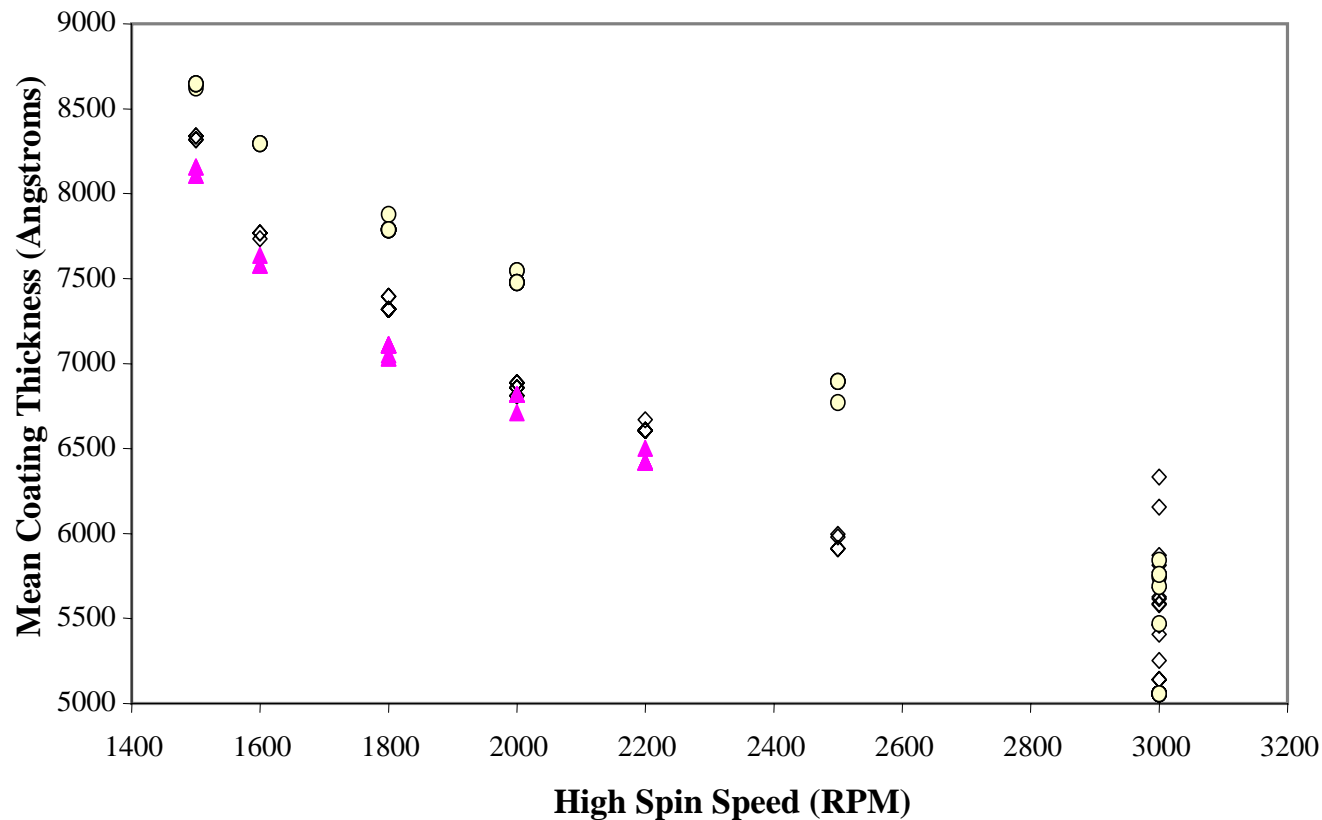


Spin coated at 3000 RPM
in 100% solvent
concentrated environment:
6215 μm with 12 \AA



Spin coated at 1500 RPM
in 100% solvent
concentrated environment:
8414 μm with 6 \AA

Mean Coating Thickness



Emslie et al.'s predictive model of coating thickness without evaporation

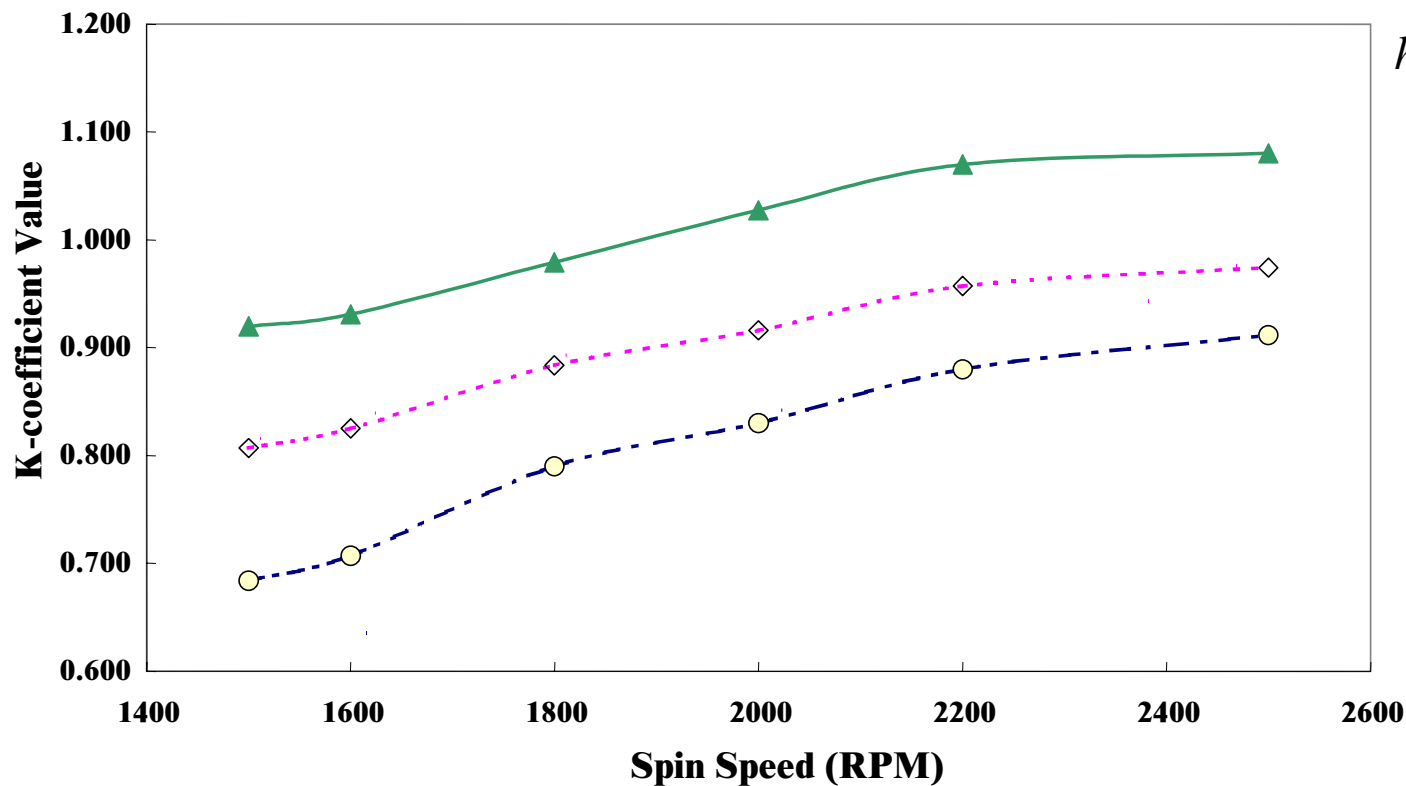
$$h_f \sim \frac{h_0}{\left[1 + 4\left(\frac{\rho\omega^2}{3\mu}\right)h_0^2 t\right]^{1/2}}$$

Proportional Coefficient

$$K(c, H, \omega, t)$$

- “o”: 20 seconds spin coating time
- “◇”: 30 seconds spin coating time
- “△”: 40 seconds spin coating time

Experimental Estimation of Coefficient $K(c, H, \omega, t)$



$$h_f = \frac{K(c, H, \omega, t)h_0}{\left[1 + 4\left(\frac{\rho\omega^2}{3\mu}\right)h_0^2t\right]^{1/2}}$$

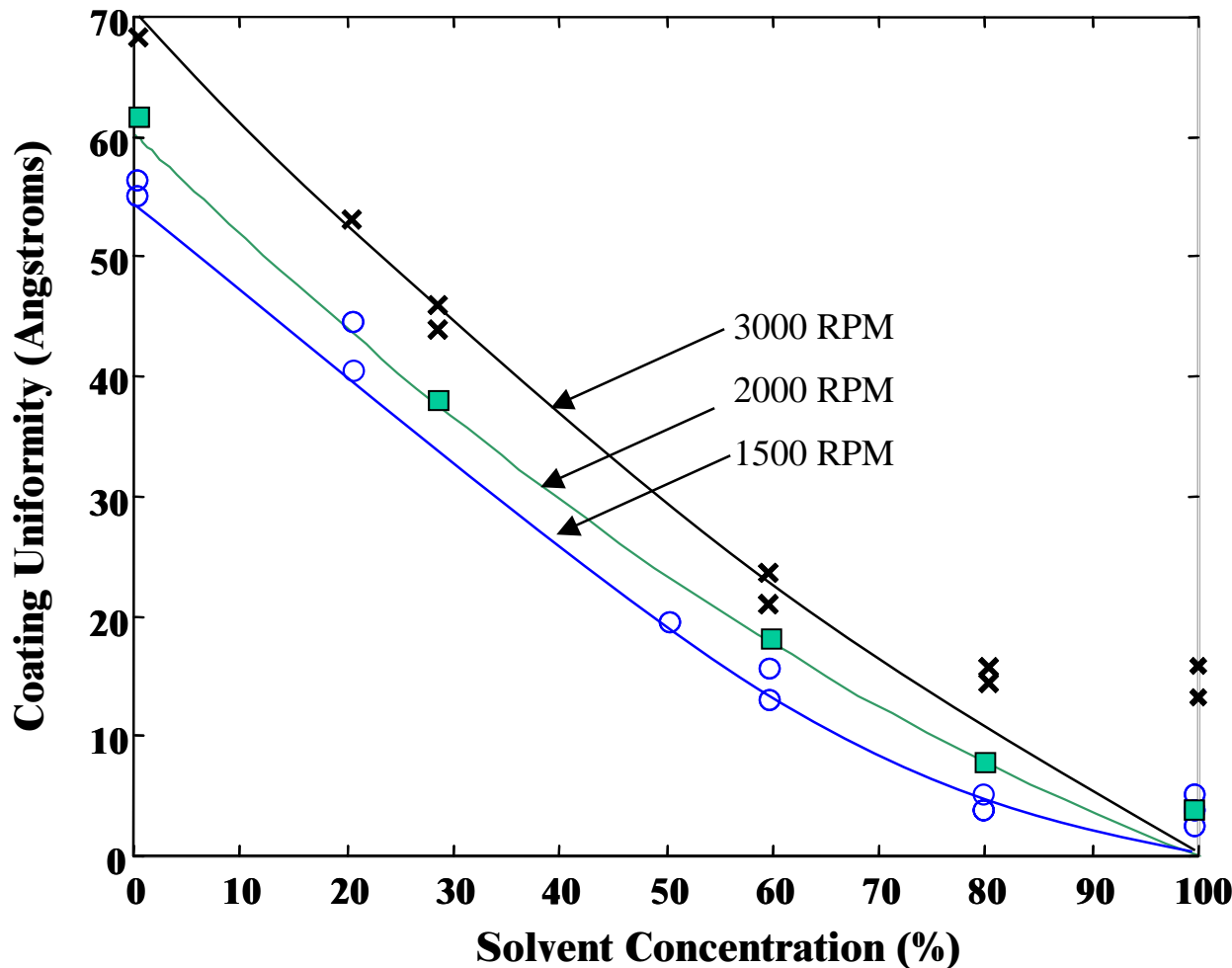
$K(c, H, \omega, t)$

$c = 100\%$

$H = 43 \sim 46\%$

- “o”: 20 seconds
spin coating time
- “◇”: 30 seconds
spin coating time
- “△”: 40 seconds
spin coating time

Prediction of Coating Uniformity



**Bornside et al.'s
predictive model
of coating thickness
with evaporation**

$$h_f \sim [k(c, H, r, \omega)]^{\frac{1}{3}}$$

Mass Transfer Coefficient

$$k(c, H, r, \omega)$$

with: $H = 43 \sim 46\%$

“x”: 3000 RPM

“□”: 2000 RPM

“○”: 1500 RPM

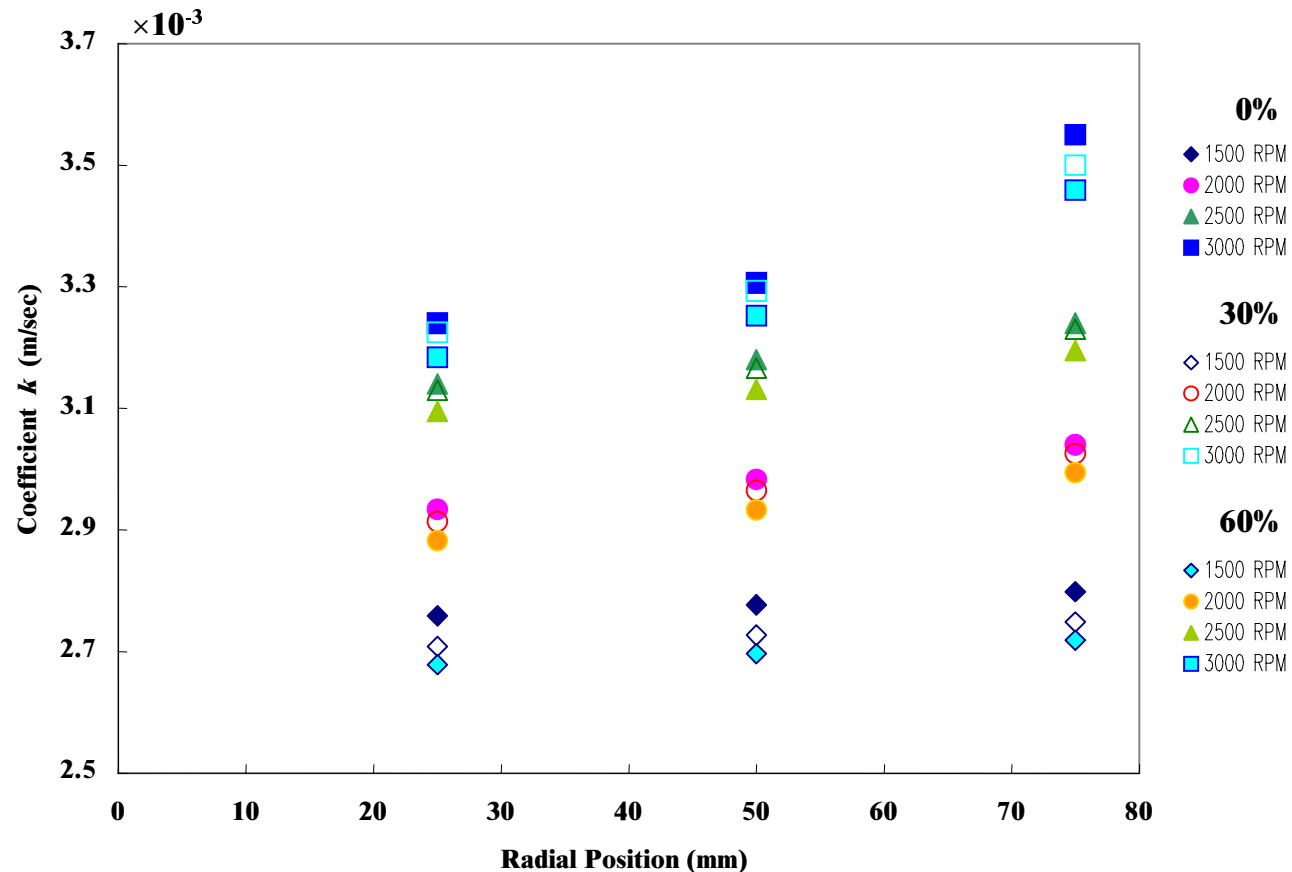
Experimental Estimation of Coefficient $k(c, H, r, \omega)$

$$h_{mean} = \frac{1}{N} (1 - x_0) \left[\left(\frac{3\mu}{2\rho^2\omega^2} \right) \frac{p^* M}{RT} x_0 \right]^{1/3} \sum_{n=1}^N k_n^{1/3}$$

N : Number of measured points

$$\sigma = \sqrt{\frac{1}{N} \sum_{n=1}^N (h_{mean} - h_f)^2}$$

σ : Coating uniformity



CONCLUSIONS



- **Extrusion-spin coating can minimize amount of photoresist and solvent use and meet desired coating uniformity**
- **Coating thickness and uniformity can be predicted by analyzing $K(c, H, \omega, t)$ and $k(c, H, r, \omega)$, respectively**

FUTURE WORK



- **Improve design of solvent vapor generating system to minimize use of solvent**
- **Improve design of coating chamber to maintain 100% solvent concentration**